## Notice of References Cited Application/Control No. 10/535,160 Applicant(s)/Patent Under Reexamination NEWKIRK ET AL. Examiner Anthony Weier Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0149649	08-2004	Uchiyama, Seiji	210/600
*	В	US-6,588,331	07-2003	Thibodeau, Pierre	100/112
*	С	US-6,800,308	10-2004	Maenz et al.	426/44
*	D	US-7,090,887	08-2006	Newkirk et al.	426/629
*	Е	US-4,481,118	11-1984	Heissenberger et al.	210/783
	F	US-			
	G	US-			
	Ι	US-			
	_	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	J	Vincent Horizontal Press. http://web.archive.org/web/20020617230836/http://www.vincentcorp.com/brochure/other.html. Published 6-2002.			
	<b>V</b>				
	w				
	×				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.